Unit: mm

TOSHIBA Field-Effect Transistor Silicon N / P Channel MOS Type

SSM6L35FE

- High-Speed Switching Applications
- Analog Switch Applications

N-ch: 1.2-V drive
P-ch: 1.2-V drive
N-ch, P-ch, 2-in-1

• Low ON-resistance Q1 N-ch: R_{on} = 20 Ω (max) (@V_{GS} = 1.2 V)

: $R_{on} = 8 \Omega \text{ (max) } (@V_{GS} = 1.5 \text{ V})$

: $R_{on} = 4 \Omega \text{ (max) } (@V_{GS} = 2.5 \text{ V})$

: $R_{on} = 3 \Omega \text{ (max) } (@V_{GS} = 4.0 \text{ V})$

Q2 P-ch: R_{on} = 44 Ω (max) (@V_{GS} = -1.2 V)

: R_{on} = 22 Ω (max) (@V_{GS} = -1.5 V)

: R_{OI} = 11 Ω (max) (@V_{GS} = -2.5 V) : R_{OI} = 8 Ω (max) (@V_{GS} = -4.0 V)

Q1 Absolute Maximum Ratings (Ta = 25°C)

| Characteristics | Symbol | Rating | Unit | |
|----------------------|-----------|----------------|------|----|
| Drain-source voltage | V_{DSS} | 20 | ٧ | |
| Gate-source voltage | V_{GSS} | ±10 | V | |
| Drain current | DC | I _D | 180 | mA |
| | Pulse | I_{DP} | 360 | MA |

Q2 Absolute Maximum Ratings (Ta = 25°C)

| Characteristics | | Symbol | Rating | Unit |
|----------------------|-------|----------------|--------|------|
| Drain-source voltage | | V_{DSS} | -20 | ٧ |
| Gate-source voltage | | V_{GSS} | ±10 | ٧ |
| Drain current | DC | I _D | -100 | mA |
| | Pulse | I_{DP} | -200 | IIIA |

Absolute Maximum Ratings (Ta = 25 °C) (Common to the Q1, Q2)

| Characteristic | Symbol | Rating | Unit | |
|---------------------------|-------------------------|------------|------|--|
| Drain power dissipation | P _D (Note 1) | 150 | mW | |
| Channel temperature | T _{ch} | 150 | °C | |
| Storage temperature range | T _{stg} | -55 to 150 | °C | |

Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings.

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

Note 1: Total rating

Mounted on an FR4 board (25.4 mm \times 25.4 mm \times 1.6 mm, Cu Pad: 0.135 mm² \times 6)

Start of commercial production 2008-03

1.6±0.05 0.55±0.05 0.55±0.05 0.55±0.05 0.5±0.05 0.2±0.05 0.2±0.05

1.6±0.05

ES6 2.Gate1 5.Gate2 3.Drain2 6.Drain1

1.Source1 4.Source2

JEITA -TOSHIBA 2-2N1D

Weight: 3.0 mg (typ.)

JEDEC

Q1 Electrical Characteristics (Ta = 25°C)

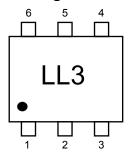
| Charae | cteristics | Symbol | Test Condition | | Min | Тур. | Max | Unit |
|------------------------------|---------------|----------------------|--|----------|-----|------|------|------|
| Gate leakage curre | ent | I _{GSS} | $V_{GS} = \pm 10 \text{ V}, V_{DS} = 0 \text{ V}$ | | _ | _ | ±10 | μΑ |
| Drain-source brea | kdown voltage | V (BR) DSS | $I_D = 0.1 \text{ mA}, V_{GS} = 0V$ | | 20 | _ | _ | V |
| Drain cutoff currer | nt | I _{DSS} | V _{DS} = 20 V, V _{GS} = 0V | | _ | _ | 1 | μΑ |
| Gate threshold vol | tage | V _{th} | $V_{DS} = 3 \text{ V}, I_{D} = 1 \text{ mA}$ | | 0.4 | _ | 1.0 | V |
| Forward transfer a | dmittance | Y _{fs} | $V_{DS} = 3 \text{ V}, I_D = 50 \text{ mA}$ (Note 2) | | 115 | _ | _ | mS |
| | | | $I_D = 50 \text{ mA}, V_{GS} = 4 \text{ V}$ | (Note 2) | _ | 1.5 | 3 | |
| Drain aguras ON | | D | $I_D = 50 \text{ mA}, V_{GS} = 2.5 \text{ V}$ | (Note 2) | _ | 2 | 4 | Ω |
| Drain–source ON-resistance | | R _{DS} (ON) | $I_D = 5 \text{ mA}, V_{GS} = 1.5 \text{ V}$ | (Note 2) | _ | 3 | 8 | |
| | | | I _D = 5 mA, V _{GS} = 1.2 V | (Note 2) | _ | 5 | 20 | |
| Input capacitance | | C _{iss} | V _{DS} = 3 V, V _{GS} = 0V, f = 1 MHz | | _ | 9.5 | _ | |
| Reverse transfer capacitance | | C _{rss} | | | _ | 4.1 | _ | pF |
| Output capacitance | | Coss | | | _ | 9.5 | _ | |
| Switching time | Turn-on time | t _{on} | $V_{DD} = 3 \text{ V}, I_D = 50 \text{ mA},$ $V_{GS} = 0 \text{ to } 2.5 \text{ V}$ | | _ | 115 | _ | |
| | Turn-off time | t _{off} | | | _ | 300 | _ | ns |
| Drain-source forward voltage | | V _{DSF} | $I_D = -180 \text{ mA}, V_{GS} = 0V$ | (Note 2) | _ | -0.9 | -1.2 | V |

Q2 Electrical Characteristics (Ta = 25°C)

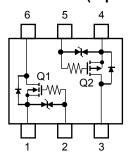
| Charac | cteristics | Symbol | Test Condition | | Min | Тур. | Max | Unit |
|------------------------------|------------------------------|----------------------|---|----------|------|------|------|------|
| Gate leakage curre | ent | I _{GSS} | $V_{GS} = \pm 10 \text{ V}, V_{DS} = 0 \text{ V}$ | | _ | _ | ±10 | μА |
| Drain-source brea | kdown voltage | V (BR) DSS | I _D = -0.1 mA, V _{GS} = 0 V | | -20 | _ | _ | V |
| Drain cutoff curren | t | I _{DSS} | $V_{DS} = -20 \text{ V}, V_{GS} = 0 \text{ V}$ | | _ | _ | -1 | μΑ |
| Gate threshold vol | tage | V _{th} | $V_{DS} = -3 \text{ V}, I_{D} = -1 \text{ mA}$ | | -0.4 | _ | -1.0 | ٧ |
| Forward transfer a | dmittance | Y _{fs} | $V_{DS} = -3 \text{ V}, I_{D} = -50 \text{ mA}$ | (Note 2) | 77 | _ | _ | mS |
| Drain-source ON-resistance | | R _{DS (ON)} | $I_D = -50 \text{ mA}, V_{GS} = -4 \text{ V}$ | (Note 2) | _ | 4.3 | 8 | Ω |
| | | | $I_D = -50 \text{ mA}, V_{GS} = -2.5 \text{ V}$ | (Note 2) | | 5.6 | 11 | |
| | | | $I_D = -5 \text{ mA}, V_{GS} = -1.5 \text{ V}$ | (Note 2) | _ | 8.2 | 22 | |
| | | | I _D = -2 mA, V _{GS} = -1.2 V | (Note 2) | _ | 11 | 44 | |
| Input capacitance | capacitance C _{iss} | | | | 12.2 | _ | | |
| Reverse transfer capacitance | | C _{rss} | $V_{DS} = -3 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$ | | _ | 6.5 | _ | pF |
| Output capacitance | | C _{oss} | | _ | 10.4 | _ | | |
| Switching time | Turn-on time | t _{on} | $V_{DD} = -3 \text{ V}, I_D = -50 \text{ mA},$ $V_{GS} = 0 \text{ to } -2.5 \text{ V}$ | | _ | 175 | _ | |
| | Turn-off time | t _{off} | | | _ | 251 | _ | ns |
| Drain–source forward voltage | | V _{DSF} | $I_D = 100 \text{ mA}, V_{GS} = 0 \text{ V}$ | (Note 2) | _ | 0.83 | 1.2 | V |

Note 2: Pulse test

Marking



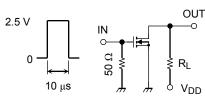
Equivalent Circuit (top view)



2015-09-09

Q1 Switching Time Test Circuit

(a) Test Circuit



 $V_{DD} = 3 V$ Duty $\leq 1\%$

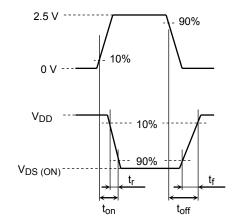
 V_{IN} : t_r , $t_f < 5$ ns

 $(Z_{out} = 50 \Omega)$ Common Source

 $Ta = 25^{\circ}C$

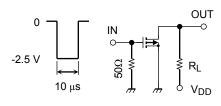


(c) V_{OUT}



Q2 Switching Time Test Circuit

(a) Test Circuit



 $V_{DD} = -3 V$

Duty ≤ 1%

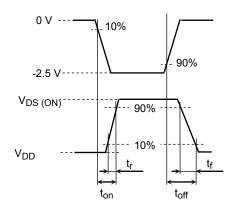
 V_{IN} : t_r , $t_f < 5$ ns $(Z_{out} = 50 \Omega)$

 $(Z_{out} = 50 \Omega)$ Common Source

 $Ta = 25^{\circ}C$

(b) V_{IN}





Q1 Usage Considerations

Let V_{th} be the voltage applied between gate and source that causes the drain current (I_D) to below (1 mA for the Q1 of the SSM6L35FE). Then, for normal switching operation, $V_{GS(on)}$ must be higher than V_{th} , and $V_{GS(off)}$ must be lower than V_{th} . This relationship can be expressed as: $V_{GS(off)} < V_{th} < V_{GS(on)}$.

Take this into consideration when using the device.

Q2 Usage Considerations

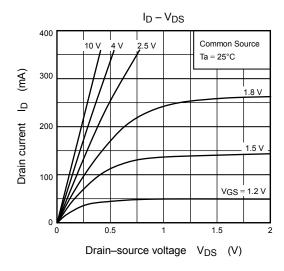
Let V_{th} be the voltage applied between gate and source that causes the drain current (I_D) to below (-1 mA for the Q2 of the SSM6L35FE). Then, for normal switching operation, $V_{GS(on)}$ must be higher than V_{th} , and $V_{GS(off)}$ must be lower than V_{th} . This relationship can be expressed as: $V_{GS(off)} < V_{th} < V_{GS(on)}$.

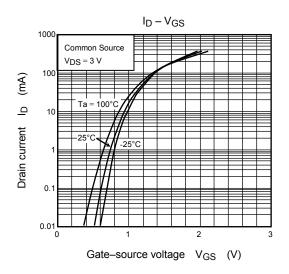
Take this into consideration when using the device.

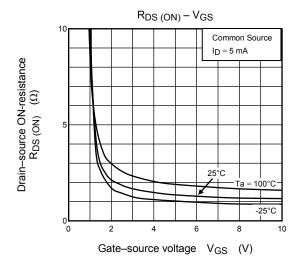
Handling Precaution

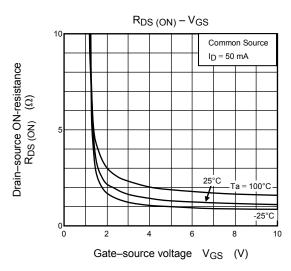
When handling individual devices that are not yet mounted on a circuit board, make sure that the environment is protected against electrostatic discharge. Operators should wear antistatic clothing, and containers and other objects that come into direct contact with devices should be made of antistatic materials.

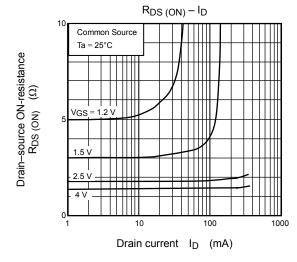
Q1 (N-ch MOSFET)

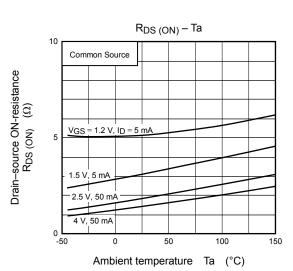




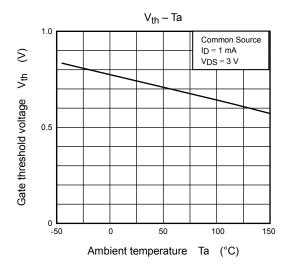


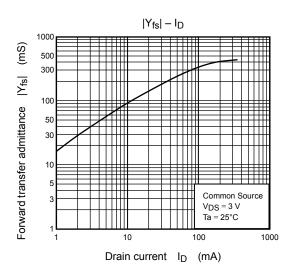


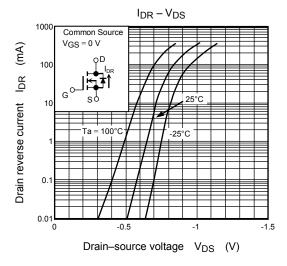


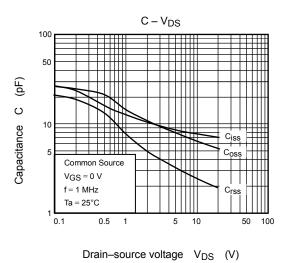


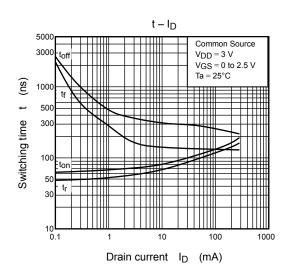
Q1 (N-ch MOSFET)





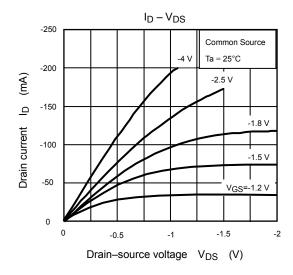


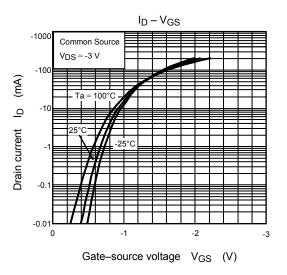


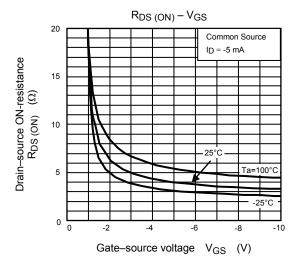


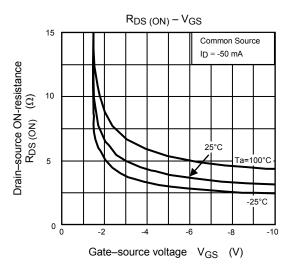
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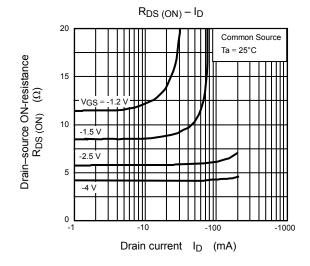
Q2 (P-ch MOSFET)

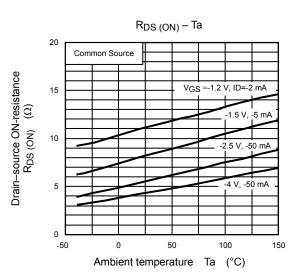






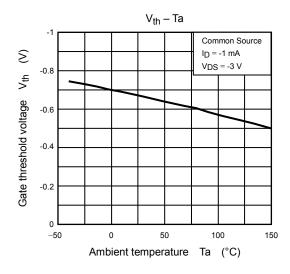


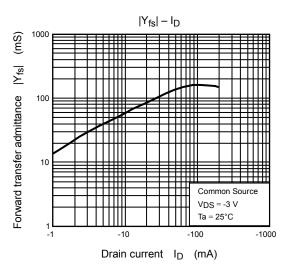


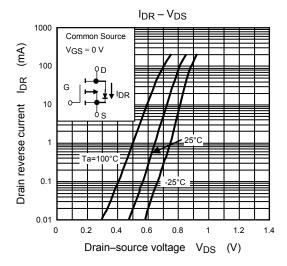


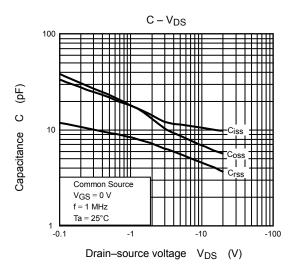
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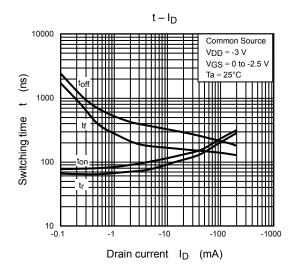
Q2 (P-ch MOSFET)

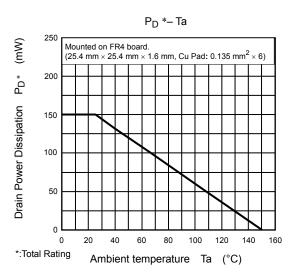












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